


<b>Search Notes</b> 	<b>Application/Control No.</b> 10695259	<b>Applicant(s)/Patent Under Reexamination</b> TAN, WAI-TIAN
	<b>Examiner</b> Nguyen-Ba, Hoang-Vu A	<b>Art Unit</b> 2623

SEARCHED			
Class	Subclass	Date	Examiner
725	149	8/23/07	HAN

SEARCH NOTES		
Search Notes	Date	Examiner
East Text Search -- USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB	8/23/07	HAN

INTERFERENCE SEARCH			
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